

**Notice of References Cited**

Application/Control No.

09/910,371

Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

2857

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**U.S. PATENT DOCUMENTS**

	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-4,990,893	02-1991	Kiluk	340/573.1
B	US-5,555,195	09-1996	Jensen et al.	700/276
C	US-2003/0061249	03-2003	Ramaswamy et al.	708/136
D	US-6,424,929	07-2002	Dawes	702/179
E	US-2001/0020219	09-2001	Kishlock et al.	702/61
F	US-2003/0014205	01-2003	Tabor	702/84
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
	T				

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Carey et al., "Resistant and Test-Based Outlier Rejection: Effects on Gaussian One- and Two-Sample Inference". Technometrics, Vol. 39, No. 3. 1999.			
	V	Sematech, "The Engineers Statistics Internet (ESI) Handbook: Grubbs' Test for Outliers." 1999.			
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.